Session Program

15–20 Jun 2014

2014 CAP Congress / Congrès de l'ACP 2014

(R1-3) Ion Beam Analysis and Modification - DCMMP / Analyse et modification de faisceaux d'ions - DPMCM

Laurentian University / Université Laurentienne
Sudbury, Ontario

Wednesday 18 June

08:45

(R1-3) Ion Beam Analysis and Modification - DCMMP / Analyse et modification de faisceaux d'ions - DPMCM

Session | **Location:** Laurentian University / Université Laurentienne, C-304, Sudbury, Ontario | **Convener:** François Schiettekatte

08:45–09:00 **High Resolution Depth Profiling for Studying Titanium Oxidation**

Speaker
Mr Mitchell Brocklebank

09:00–09:15 **Characterization of PICASSO/PICO detectors using University of Montreal Tandem Van de Graaff accelerator**

Speaker
Mathieu Laurin

09:15–09:30 **Measurement of hyperuniformity in pure amorphous silicon**

Speaker
Sjoerd Roorda

09:30–09:45 **Defect complex evolution in semiconductors: long-range elastic interactions matter**

Speaker
François Schiettekatte

09:45–10:00 **Medium energy ions for thin films and monolayers**

Speaker
Lyudmila Goncharova

10:00–10:30 **Toward pump-probe experiments of defect dynamics with pulsed ion beams**

Speaker
Peter Seidl

10:30